## Search Notes



Αp	plica	tion/C	Contro	l No

10585642

Applicant(s)/Patent Under Reexamination

YANO ET AL.

Examiner

Art Unit

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Rachel L Zhang 1795

## SEARCHED

Class	Subclass	Date	Examiner		
430	48, 108.2	6/3/2010	RLB		
528	361	6/3/2010	RLB		
399	130, 50	6/3/2010	RLB		
430	111.32, 111.35	12/01/2010	RLZ		

## SEARCH NOTES

Search Notes	Date	Examiner
inventorship search	6/3/2010	RLB
text searc in EAST (see search history)h	6/3/2010	RLB
consulted with SPE Mark Huff	6/3/2010	RLB
updated text search in EAST (see search history)	12/01/2010	RLZ
consulted with Chris RoDee	12/01/2010	RLZ

## INTERFERENCE SEARCH

Class	Subclass	Date	Examiner			
430	111.32, 111.35, 48, 108.2	08/25/2011	rlz			
528	361	08/25/2011	rlz			
399	130, 50	08/25/2011	rlz			

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